

SUPER FAST RECTIFIER

VOLTAGE RANGE: 200 V
CURRENT: 5.0 A

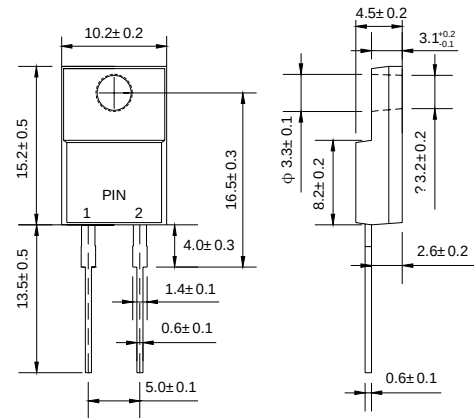
FEATURES

- ◇ Metal-Semiconductor junction with guard ring
- ◇ Epitaxial construction
- ◇ Low forward voltage drop, low switching losses
- ◇ High surge capability
- ◇ For use in low voltage, high frequency inverters free wheeling, and polarity protection applications
- ◇ The plastic material carries U/L recognition 94V-0

MECHANICAL DATA

- ◇ Case: JEDEC ITO-220AC
- ◇ Terminals: Solderable per MIL-STD-202, Method 208
- ◇ Polarity: As marked
- ◇ Weight: 0.056 ounces, 1.587 gram
- ◇ Mounting position: Any

ITO-220AC



Dimensions in millimeters

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified.

Single phase, half wave, 50 Hz, resistive or inductive load. For capacitive load, derate by 20%.

		FML- G12S	UNITS
Maximum recurrent peak reverse voltage	V_{RRM}	200	V
Maximum RMS voltage	V_{RMS}	140	V
Maximum DC blocking voltage	V_{DC}	200	V
Maximum average forward rectified current @ $T_C = 100^\circ\text{C}$	$I_{F(AV)}$	5.0	A
Peak forward surge current 10ms single half-sine-wave superimposed on rated load	I_{FSM}	65	A
Maximum instantaneous forward voltage ($I_F = 5.0\text{A}$)	V_F	0.98	V
Maximum reverse current @ $T_J = 25^\circ\text{C}$ at rated DC blocking voltage @ $T_J = 100^\circ\text{C}$	I_R	0.25 1.0	mA
Maximum reverse recovery time (Note1)	t_{rr}	30	ns
Typical thermal resistance (Note2)	$R_{\theta JC}$	4.0	$^\circ\text{C/W}$
Operating junction temperature range	T_J	- 55 ---- + 150	$^\circ\text{C}$
Storage temperature range	T_{STG}	- 55 ---- + 150	$^\circ\text{C}$

NOTE: 1. Measured with $I_F = 0.5\text{A}$, $I_R = 1\text{A}$, $I_{rr} = 0.25\text{A}$.
2. Thermal resistance junction to case.

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FIG.1 – TYPICAL FORWARD CHARACTERISTIC

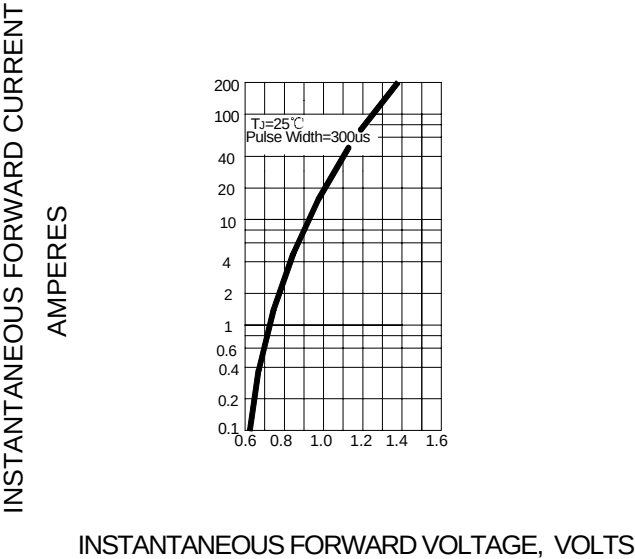


FIG.2- FORWARD DERATING CURVE

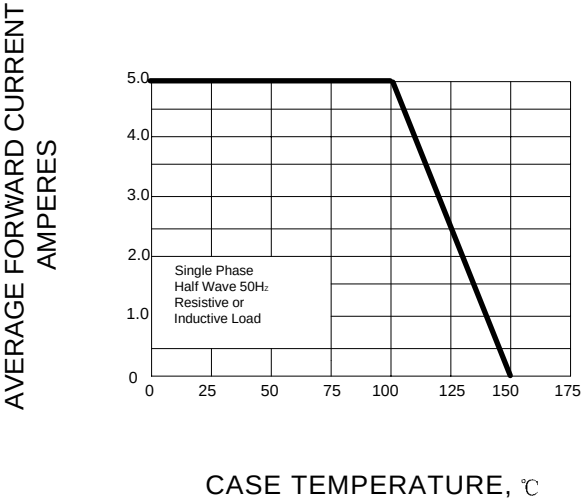


FIG.3- PEAK FORWARD SURGE CURRENT

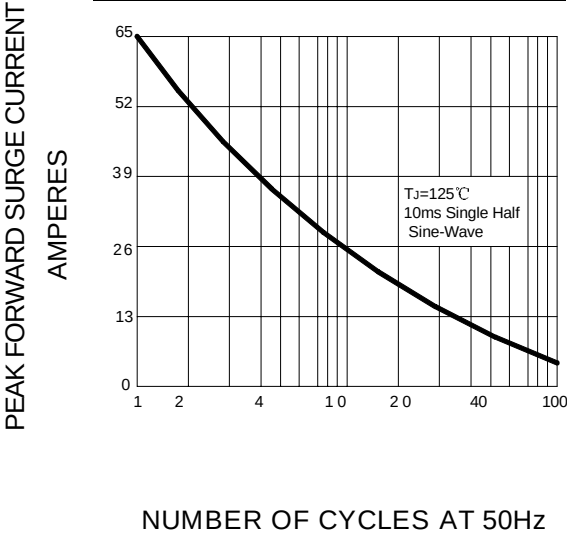


FIG.4 – TYPICAL REVERSE CHARACTERISTICS

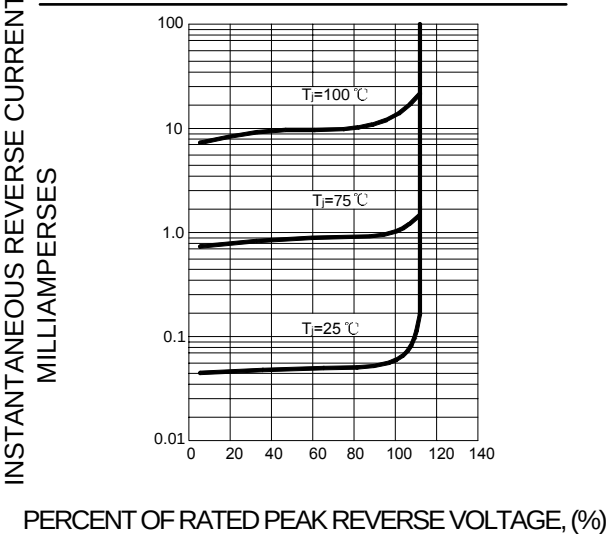


FIG.5 – REVERSE RECOVERY TIME CHARACTERISTIC AND TEST CIRCUIT DIAGRAM

